

# N-Channel Enhancement Mode Power MOSFET

#### **Description**

The HM60N03 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

#### **General Features**

V<sub>DS</sub> =30V,I<sub>D</sub> =60A

 $R_{DS(ON)}$  < 11m $\Omega$  @  $V_{GS}$ =10V

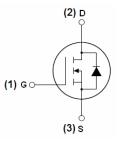
 $R_{DS(ON)}$  < 13m $\Omega$  @  $V_{GS}$ =4.5V

- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Good stability and uniformity with high E<sub>AS</sub>
- Excellent package for good heat dissipation
- Special process technology for high ESD capability

## **Application**

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

100% UIS TESTED!



#### Schematic diagram



#### Marking and pin Assignment



TO-220-3L top view

#### **Package Marking And Ordering Information**

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM60N03	HM60N03	TO-220-3L	-	-	-

### Absolute Maximum Ratings (TA=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	V <sub>DS</sub>	30	V
Gate-Source Voltage	V <sub>GS</sub>	±20	V
Drain Current-Continuous	I <sub>D</sub>	60	А
Drain Current-Continuous(T <sub>C</sub> =100°C)	I <sub>D</sub> (100℃)	42	Α
Pulsed Drain Current	I <sub>DM</sub>	180	Α
Maximum Power Dissipation	P <sub>D</sub>	60	W
Derating factor		0.4	W/℃
Single pulse avalanche energy (Note 5)	E <sub>AS</sub>	70	mJ



Operating Junction and Storage Temperature Range	$T_{J}$ , $T_{STG}$	-55 To 175	$^{\circ}$ C
Thermal Characteristic			
Thermal Resistance, Junction-to-Case(Note 2)	R <sub>eJC</sub>	2.5	°C/W

# Electrical Characteristics (TA=25°C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Max	Unit	
Off Characteristics							
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250μA		33	-	V	
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =30V,V <sub>GS</sub> =0V	-	-	1	μA	
Gate-Body Leakage Current	I <sub>GSS</sub>	V <sub>GS</sub> =±20V,V <sub>DS</sub> =0V	-	-	±100	nA	
On Characteristics (Note 3)							
Gate Threshold Voltage	$V_{GS(th)}$	$V_{DS}=V_{GS},I_{D}=250\mu A$	1	1.8	3	V	
Drain-Source On-State Resistance	Б	V <sub>GS</sub> =10V, I <sub>D</sub> =25A	-	9	11	mΩ	
Diain-Source On-State Resistance	R <sub>DS(ON)</sub>	V <sub>GS</sub> =5V, I <sub>D</sub> =20A	20A - 11		13	11112	
Forward Transconductance	<b>g</b> FS	V <sub>DS</sub> =5V,I <sub>D</sub> =20A	15	-	-	S	
Dynamic Characteristics (Note4)							
Input Capacitance	C <sub>lss</sub>	\/ -15\/\/ -0\/	-	2000	-	PF	
Output Capacitance	Coss	$V_{DS}$ =15V, $V_{GS}$ =0V, F=1.0MHz	-	280	-	PF	
Reverse Transfer Capacitance	C <sub>rss</sub>	F-1.0IVID2	-	160	-	PF	
Switching Characteristics (Note 4)							
Turn-on Delay Time	t <sub>d(on)</sub>		-	10	-	nS	
Turn-on Rise Time	t <sub>r</sub>	V <sub>DD</sub> =15V,I <sub>D</sub> =20A	-	8	-	nS	
Turn-Off Delay Time	$t_{d(off)}$	$V_{GS}$ =10V, $R_{GEN}$ =1.8 $\Omega$	-	30	-	nS	
Turn-Off Fall Time	t <sub>f</sub>		-	5	-	nS	
Total Gate Charge	Qg	\/ -10\/  -254	-	23	-	nC	
Gate-Source Charge	$Q_{gs}$	$V_{DS}$ =10V, $I_D$ =25A, $V_{GS}$ =10V	-	7	-	nC	
Gate-Drain Charge	$Q_{gd}$	VGS-10V	-	4.5	-	nC	
Drain-Source Diode Characteristics							
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =25A	-	0.85	1.2	V	
Diode Forward Current (Note 2)	Is		-	-	40	Α	
Reverse Recovery Time	t <sub>rr</sub>	TJ = 25°C, IF = 40A	-	22	35	nS	
Reverse Recovery Charge	Qrr	di/dt = 100A/µs(Note3) -		12	20	nC	
Forward Turn-On Time	t <sub>on</sub>	Intrinsic turn-on time is negligible (turn-on is dominated by LS+LD)					

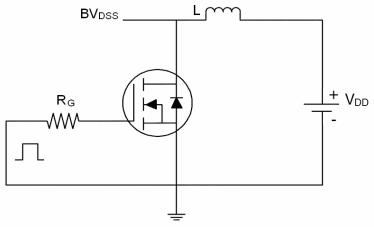
#### Notes:

- 1. Repetitive Rating: Pulse width limited by maximum junction temperature.
- **2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.
- **3.** Pulse Test: Pulse Width ≤ 300 µs, Duty Cycle ≤ 2%.
- 4. Guaranteed by design, not subject to production
- **5.** EAS condition: Tj=25  $^{\circ}$ C,V<sub>DD</sub>=15V,V<sub>G</sub>=10V,L=1mH,Rg=25 $\Omega$

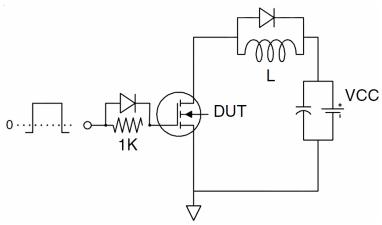


# **Test circuit**

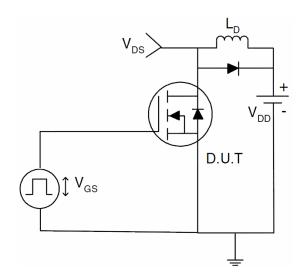
# 1) E<sub>AS</sub> test Circuits



# 2) Gate charge test Circuit:



# 3) Switch Time Test Circuit:



# TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS (Curves)

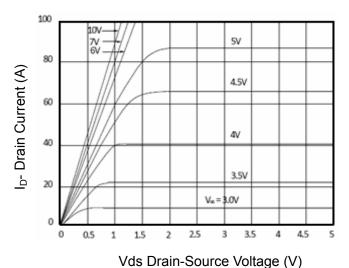
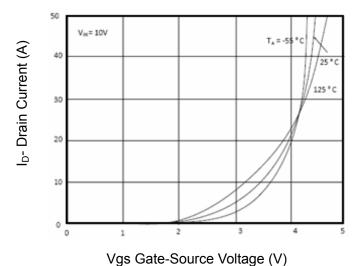


Figure 1 Output Characteristics



**Figure 2 Transfer Characteristics** 

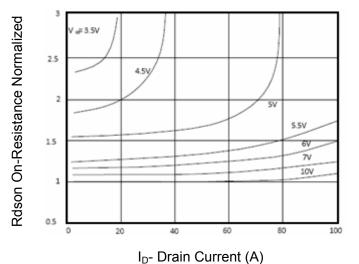


Figure 3 Rdson- Drain Current

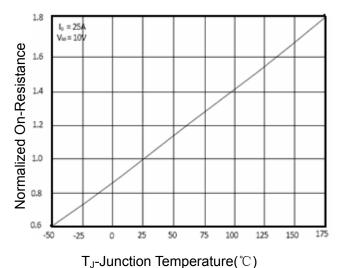


Figure 4 Rdson-JunctionTemperature

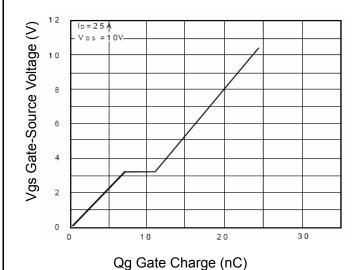


Figure 5 Gate Charge

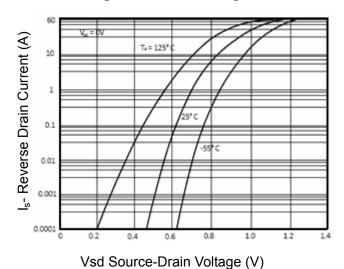


Figure 6 Source- Drain Diode Forward

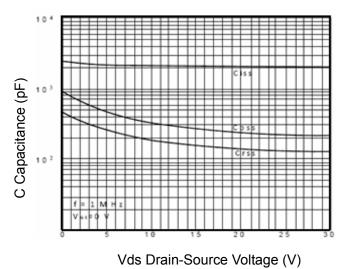


Figure 7 Capacitance vs Vds

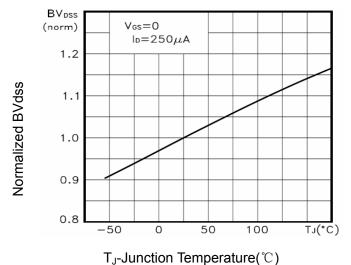


Figure 9 BV<sub>DSS</sub> vs Junction Temperature

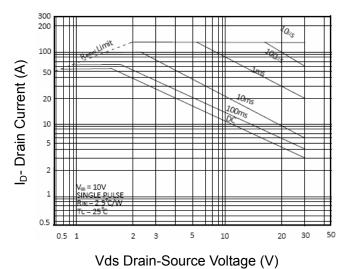
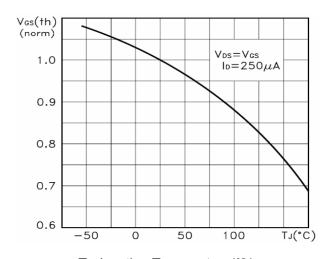
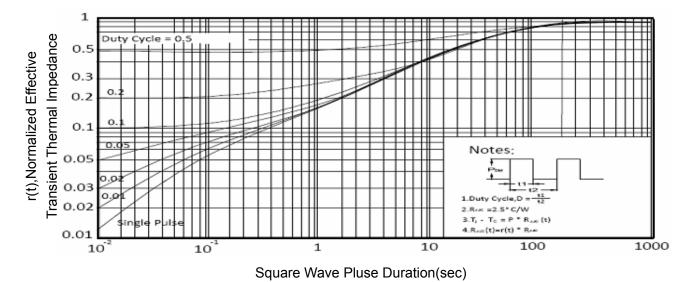


Figure 9 Cofe Operation Ar



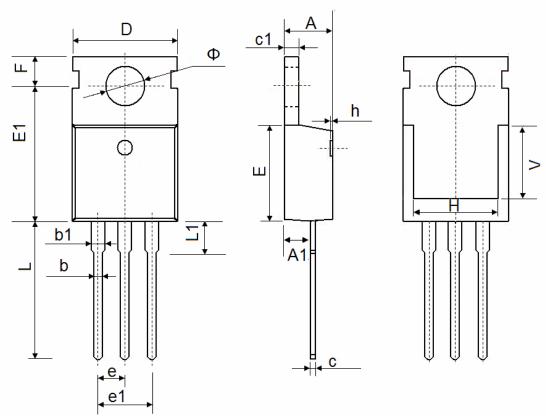
T<sub>J</sub>-Junction Temperature(°C)

Figure 8 Safe Operation Area Figure 10  $V_{GS(th)}$  vs Junction Temperature



**Figure 11 Normalized Maximum Transient Thermal Impedance** 

# **TO-220-3L Package Information**



Symbol	Dimensions	In Millimeters	Dimensions In Inches			
	Min.	Max.	Min.	Max.		
А	4.400	4.600	0.173	0.181		
A1	2.250	2.550	0.089	0.100		
b	0.710	0.910	0.028	0.036		
b1	1.170	1.370	0.046	0.054		
С	0.330	0.650	0.013	0.026		
c1	1.200	1.400	0.047	0.055		
D	9.910	10.250	0.390	0.404		
Е	8.9500	9.750	0.352	0.384		
E1	12.650	12.950	0.498	0.510		
е	2.540	2.540 TYP.		0.100 TYP.		
e1	4.980	5.180	0.196	0.204		
F	2.650	2.950	0.104	0.116		
Н	7.900	8.100	0.311	0.319		
h	0.000	0.300	0.000	0.012		
L	12.900	13.400	0.508	0.528		
L1	2.850	3.250	0.112	0.128		
V	7.500 REF.		0.295 REF.			
Ф	3.400	3.800	0.134	0.150		

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